



EV633198917

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 09/755,673  
Filing Date ..... January 5, 2001  
Inventor..... Leonard Forbes, et al.  
Assignee..... Micron Technology, Inc.  
Group Art Unit..... 2823  
Examiner ..... K.D. Nguyen  
Attorney's Docket No. .... MI22-1531  
Title ..... Methods of Forming Capacitor Structures

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Reference -See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed after the filing of the Request for Continued Examination (RCE) Application and before receipt of the first Office Action. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

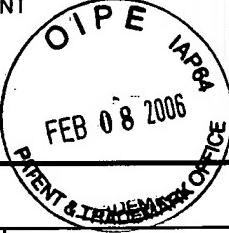
Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 2/7/06

By:

  
Robert C. Hyta  
Reg. No. 46,791

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1531		SERIAL NO. 09/755,673	
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT: Leonard Forbes, et al.			
					FILING DATE January 5, 2001		GROUP 2823	
U.S. PATENT DOCUMENTS								
*Examiner's Initials		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
	AA	6,203,613 B1	03/01	Gates, et al.				
	AB	6,509,280 B2	01/03	Choi, Sung-Je				
	AC	6,551,399 B1	04/03	Sneh, et al.				
	AD	6,576,053 B1	06/03	Kim, et al.				
	AE	6,580,111 B2	06/03	Kim, et al.				
	AF	6,664,186 B1	12/03	Callegari, et al.				
	AG	6,780,704 B1	08/04	Raaijmakers, et al.				
	AH							
	AJ							
	AK							
	AL							
	AM							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AN							
	AO							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AP							
	AQ							
EXAMINER		DATE CONSIDERED						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								